



# F30NM65

Power MOSFET

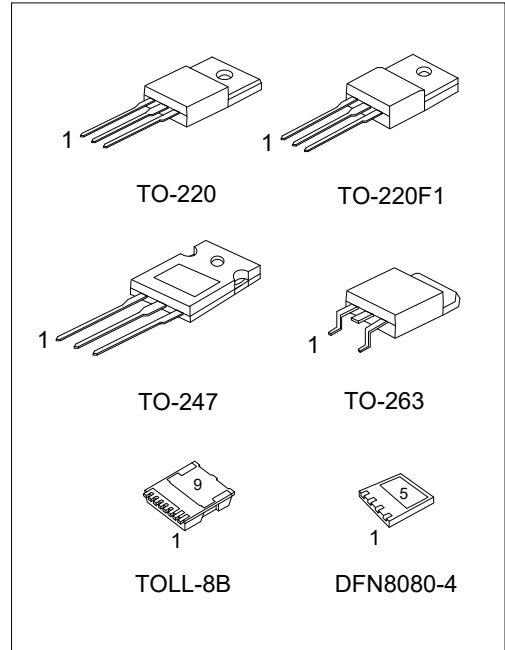
## 30A, 650V N-CHANNEL SUPER-JUNCTION MOSFET

### DESCRIPTION

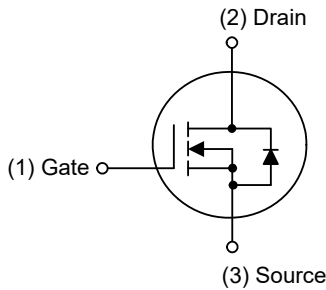
The **UTC F30NM65** is a N-Channel enhancement mode silicon gate power MOSFET with Fast Body Diode. is designed high voltage, high speed power switching applications such. such as fast switching time, low gate charge, low on-state resistance and high rugged avalanche characteristics.

### FEATURES

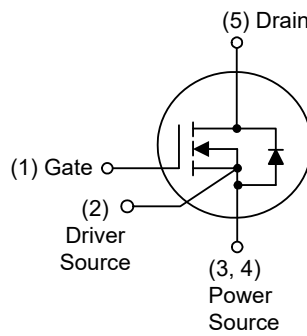
- \*  $R_{DS(ON)} \leq 0.15 \Omega @ V_{GS}=10V, I_D=15A$
- \* Fast body diode MOSFET technology
- \* Low switching losses due to reduced  $Q_{rr}$
- \* Single Pulse Avalanche Energy Rated
- \* Fast Switching Speeds
- \* Linear Transfer Characteristics
- \* High Input Impedance
- \* Avalanche energy tested



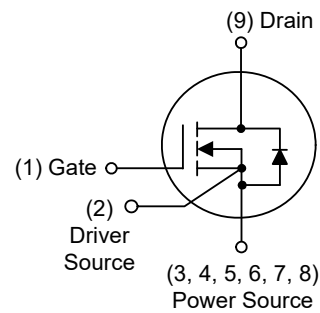
### SYMBOL



TO-220 / TO-220F1  
TO-247 / TO-263



DFN8080-4



TOLL-8B

### ORDERING INFORMATION

Ordering Number		Package	Pin Assignment									Packing
Lead Free	Halogen Free		1	2	3	4	5	6	7	8	9	
F30NM65L-TA3-T	F30NM65G-TA3-T	TO-220	G	D	S	-	-	-	-	-	-	Tube
F30NM65L-TF1-T	F30NM65G-TF1-T	TO-220F1	G	D	S	-	-	-	-	-	-	Tube
F30NM65L-TQ2-T	F30NM65G-TQ2-T	TO-263	G	D	S	-	-	-	-	-	-	Tube
F30NM65L-TQ2-R	F30NM65G-TQ2-R	TO-263	G	D	S	-	-	-	-	-	-	Tape Reel
F30NM65L-T47-T	F30NM65G-T47-T	TO-247	G	D	S	-	-	-	-	-	-	Tube
F30NM65L-T8B-R	F30NM65G-T8B-R	TOLL-8B	G	S	S	S	S	S	S	S	D	Tape Reel
F30NM65L-K04-8080-R	F30NM65G-K04-8080-R	DFN8080-4	G	S	S	S	D	-	-	-	-	Tape Reel

Note: Pin Assignment: G: Gate D: Drain S: Source

<p>F30NM65G-TA3-T</p> <p>(1) Packing Type (2) Package Type (3) Green Package</p>	<p>(1) T: Tube, R: Tape Reel (2) TA3: TO-220, TF1: TO-220F1, T47: TO-247, TQ2: TO-263, T8B: TOLL-8B, K04-8080: DFN8080-4 (3) G: Halogen Free and Lead Free, L: Lead Free</p>
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### MARKING

PACKAGE	MARKING
TO-220 / TO-220F1 TO-247 / TO-263	<p>UTC F30NM65 Lot Code → → → → → Date Code L: Lead Free G: Halogen Free 1</p>
DFN8080-4	<p>UTC F30NM65 Lot Code → • → → → → Date Code 1</p>
TOLL-8B	<p>UTC F30NM60 Lot Code → → → → → Date Code L: Lead Free G: Halogen Free 1</p>

■ ABSOLUTE MAXIMUM RATINGS ( $T_c=25^\circ\text{C}$ , unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		$V_{DSS}$	650	V
Gate-Source Voltage		$V_{GSS}$	$\pm 30$	V
Drain Current	Continuous	$I_D$	30	A
	Pulsed (Note 2)	$I_{DM}$	60	A
Avalanche Energy	Single Pulsed (Note 3)	$E_{AS}$	1188	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	10.8	V/nS
Power Dissipation	TO-220/TO-220F1 TO-263	$P_D$	40	W
	TO-247		145	W
	TOLL-8B		210	W
	DFN8080-4		70	W
Junction Temperature		$T_J$	+150	$^\circ\text{C}$
Storage Temperature		$T_{STG}$	-55 ~ +150	$^\circ\text{C}$

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating: Pulse width limited by maximum junction temperature.

3.  $L = 60\text{ mH}$ ,  $I_{AS} = 6.29\text{A}$ ,  $V_{DD} = 50\text{V}$ ,  $R_G = 25\Omega$ , Starting  $T_J = 25^\circ\text{C}$

4.  $I_{SD} \leq 30\text{A}$ ,  $di/dt \leq 200\text{A}/\mu\text{s}$ ,  $V_{DD} \leq BV_{DSS}$ , Starting  $T_J = 25^\circ\text{C}$

■ THERMAL DATA

PARAMETER		SYMBOL	RATINGS	UNIT
Junction to Ambient	TO-220/TO-220F1 TO-263	$\theta_{JA}$	62.5	$^\circ\text{C}/\text{W}$
	TO-247		40	$^\circ\text{C}/\text{W}$
	TOLL-8B/DFN8080-4		35 (Note)	$^\circ\text{C}/\text{W}$
Junction to Case	TO-220/TO-263	$\theta_{JC}$	0.96	$^\circ\text{C}/\text{W}$
	TO-220F1		3.12	$^\circ\text{C}/\text{W}$
	TO-247		0.86	$^\circ\text{C}/\text{W}$
	TOLL-8B		0.59 (Note)	$^\circ\text{C}/\text{W}$
	DFN8080-4		1.78 (Note)	$^\circ\text{C}/\text{W}$

Note: Surface mounted on 1 in<sup>2</sup> copper pad of FR4 board; 270 $^\circ\text{C}/\text{W}$  when mounted on min. copper pad.

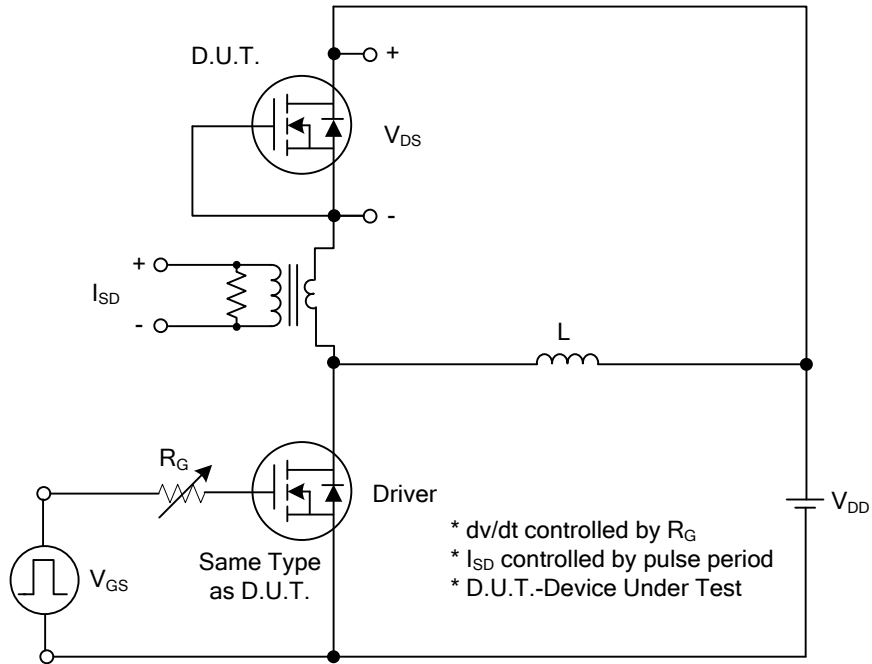
■ ELECTRICAL CHARACTERISTICS (T<sub>J</sub>=25°C, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
<b>OFF CHARACTERISTICS</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V	650			V
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =650V, V <sub>GS</sub> =0V			10	μA
Gate- Source Leakage Current	Forward	I <sub>GSS</sub>			+100	nA
	Reverse					
		V <sub>GS</sub> =-30V, V <sub>DS</sub> =0V			-100	nA
<b>ON CHARACTERISTICS</b>						
Gate Threshold Voltage	V <sub>GS(TH)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	2.5		4.5	V
Static Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =15A			0.15	Ω
<b>DYNAMIC PARAMETERS</b>						
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =25V, f=1.0MHz		2580		pF
Output Capacitance	C <sub>OSS</sub>			1750		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>			130		pF
<b>SWITCHING PARAMETERS</b>						
Total Gate Charge (Note 1)	Q <sub>G</sub>	V <sub>DS</sub> =520V, V <sub>GS</sub> =10V, I <sub>D</sub> =30A (Note1, 2)		94		nC
Gate to Source Charge	Q <sub>GS</sub>			22		nC
Gate to Drain Charge	Q <sub>GD</sub>			35		nC
Turn-ON Delay Time (Note 1)	t <sub>D(ON)</sub>	V <sub>DS</sub> =100V, V <sub>GS</sub> =10V, I <sub>D</sub> =30A, R <sub>G</sub> =25Ω (Note1, 2)		34		ns
Rise Time	t <sub>R</sub>			31		ns
Turn-OFF Delay Time	t <sub>D(OFF)</sub>			290		ns
Fall-Time	t <sub>F</sub>			128		ns
<b>SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS</b>						
Maximum Body-Diode Continuous Current	I <sub>S</sub>				30	A
Maximum Body-Diode Pulsed Current	I <sub>SM</sub>				60	A
Drain-Source Diode Forward Voltage (Note 1)	V <sub>SD</sub>	I <sub>S</sub> =30A, V <sub>GS</sub> =0V			1.4	V
Body Diode Reverse Recovery Time (Note 1)	t <sub>rr</sub>	I <sub>S</sub> =30A, V <sub>GS</sub> =0V, dI <sub>F</sub> /dt=100A/μs		232		ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>				2.1	

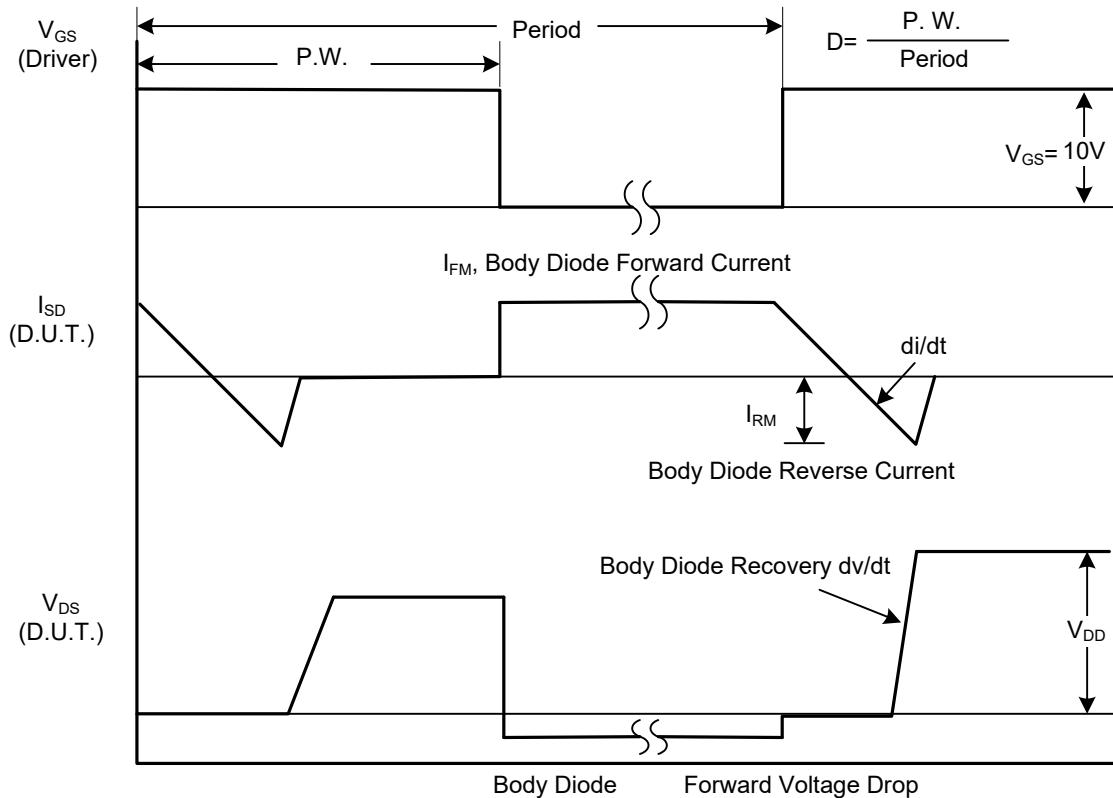
Notes: 1. Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2%.

2. Essentially independent of operating ambient temperature.

## TEST CIRCUITS AND WAVEFORMS



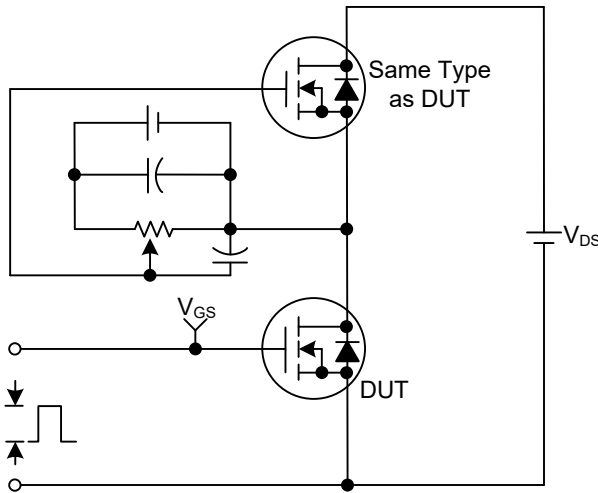
**Peak Diode Recovery dv/dt Test Circuit**



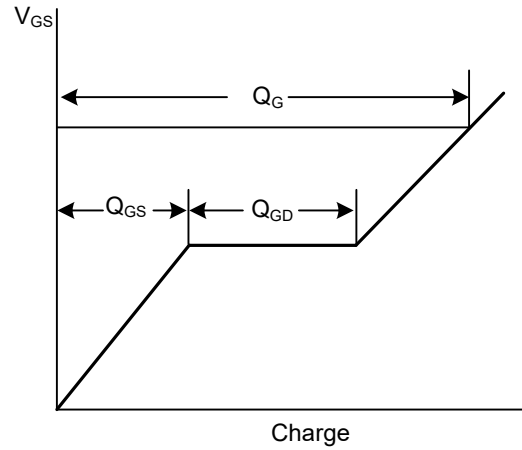
**Peak Diode Recovery dv/dt Waveforms**

## TEST CIRCUITS AND WAVEFORMS

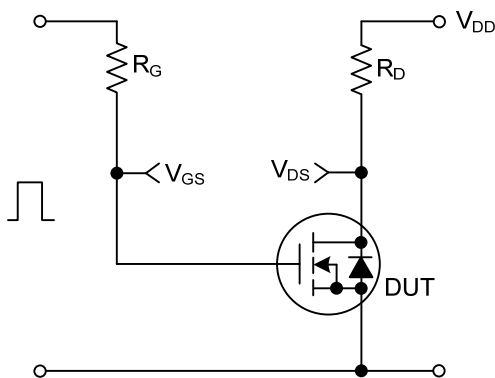
Gate Charge Test Circuit



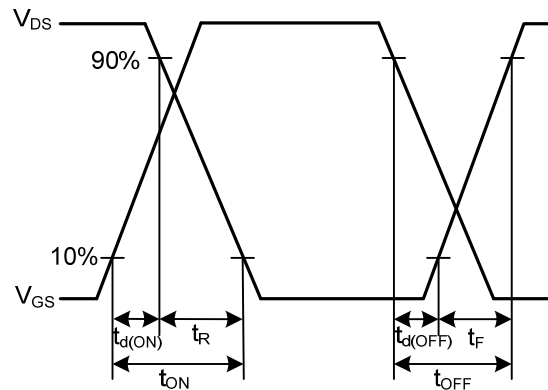
Gate Charge Waveforms



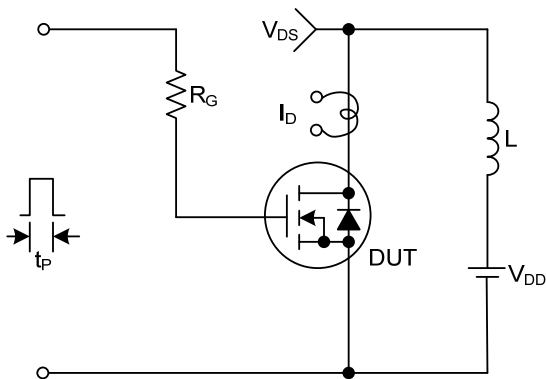
Resistive Switching Test Circuit



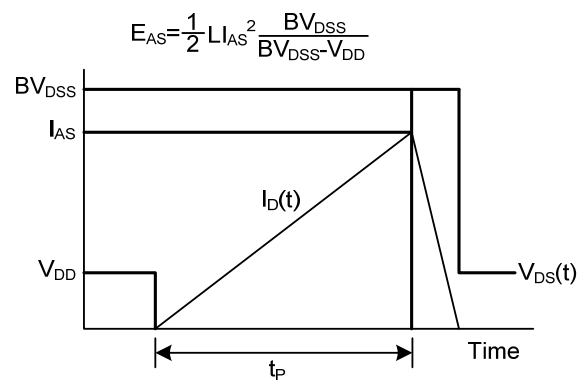
Resistive Switching Waveforms



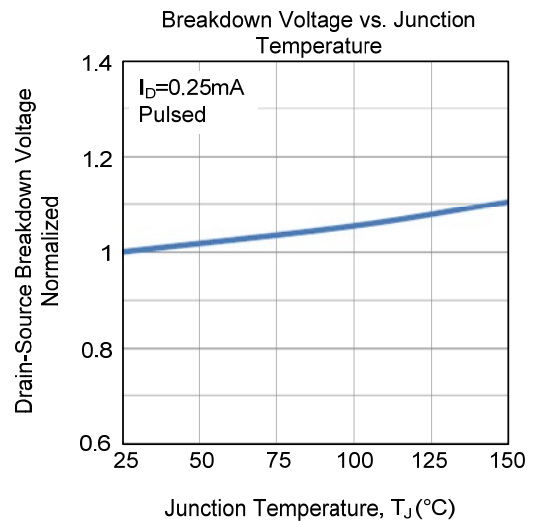
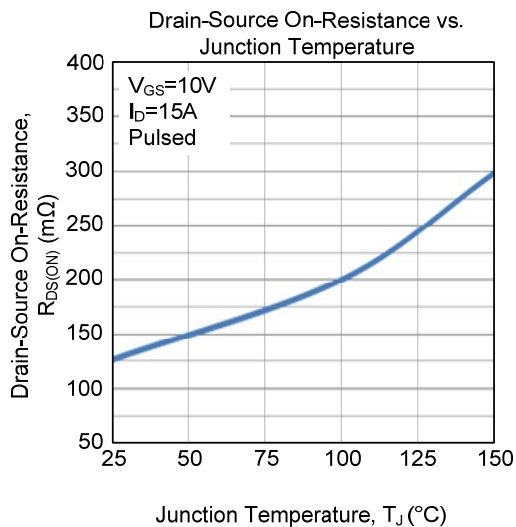
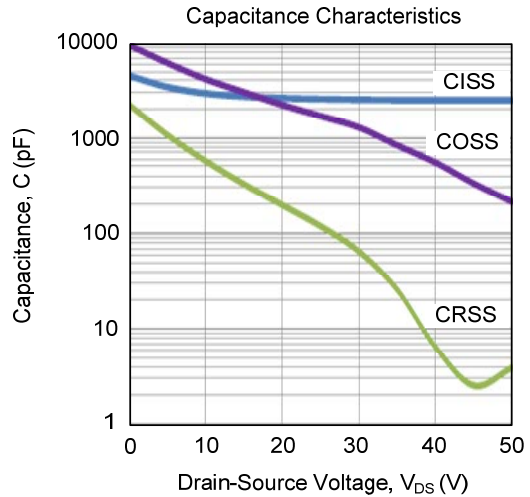
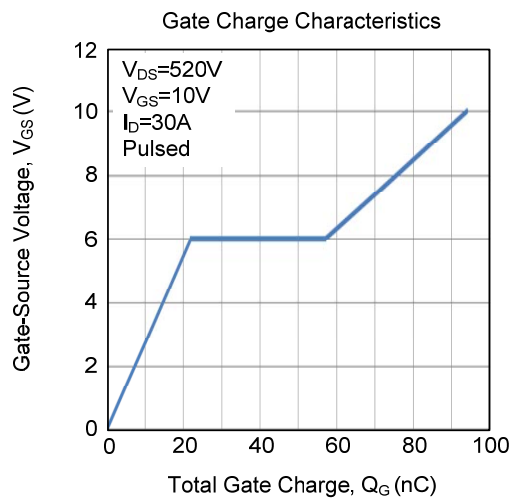
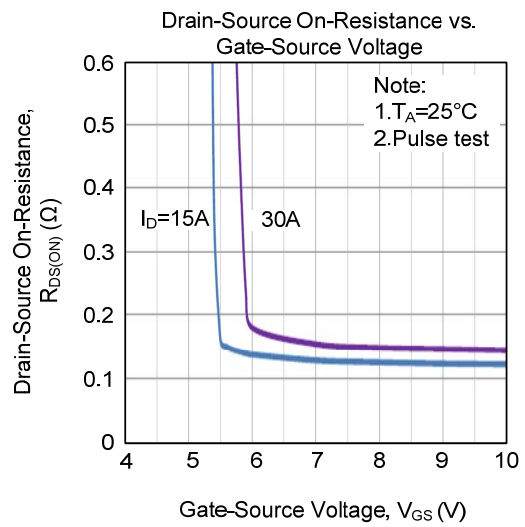
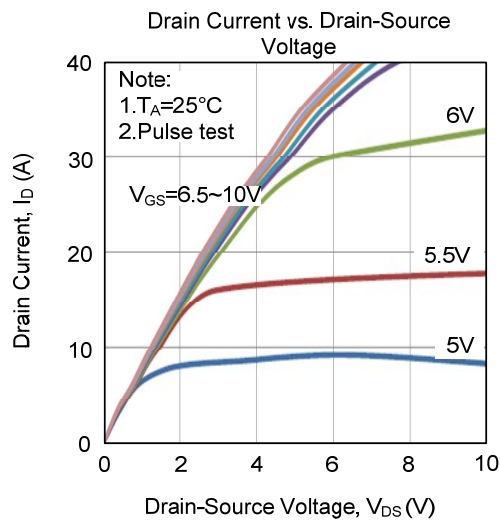
Unclamped Inductive Switching Test Circuit



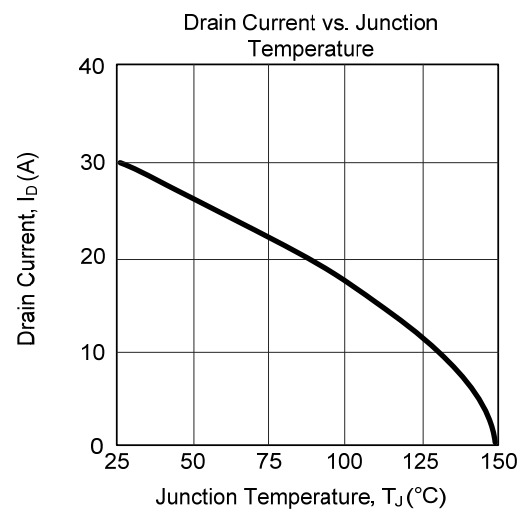
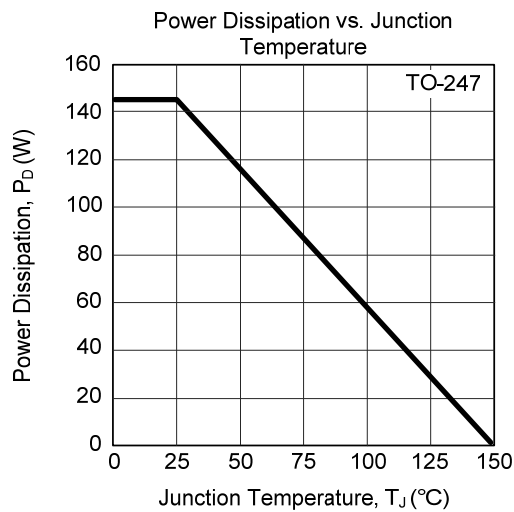
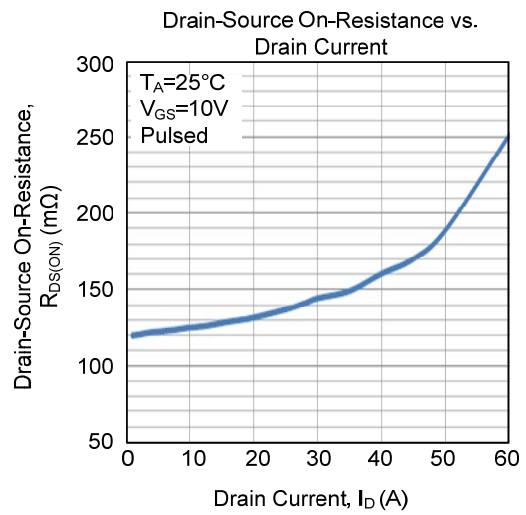
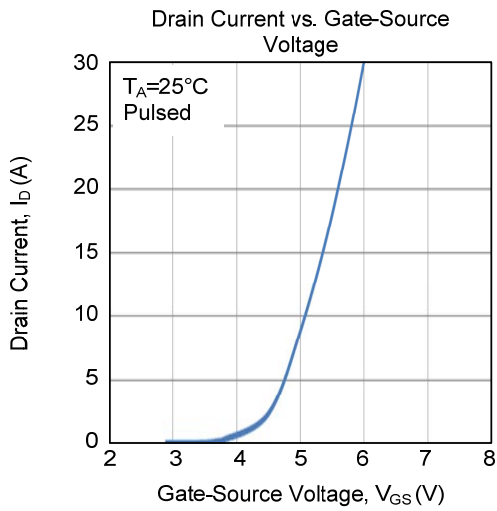
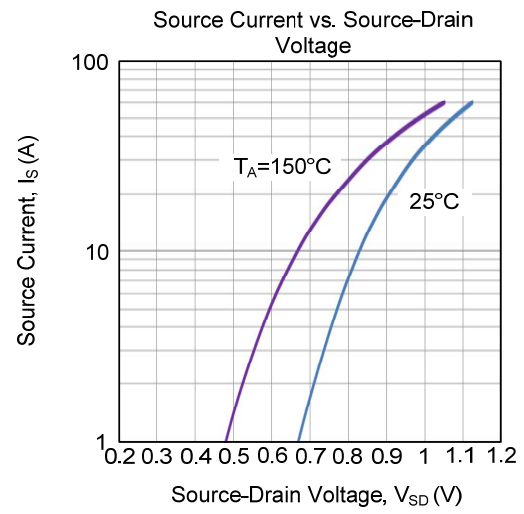
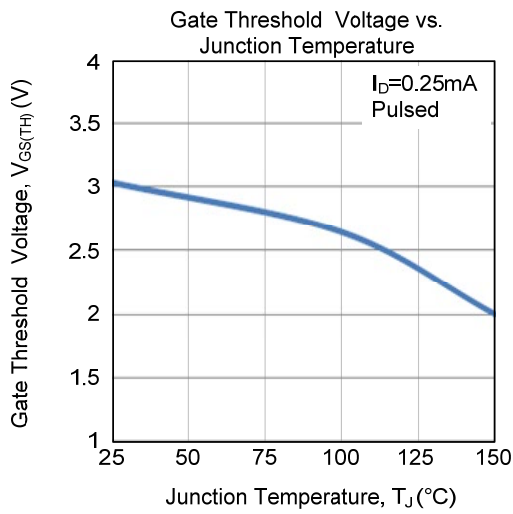
Unclamped Inductive Switching Waveforms



## TYPICAL CHARACTERISTICS

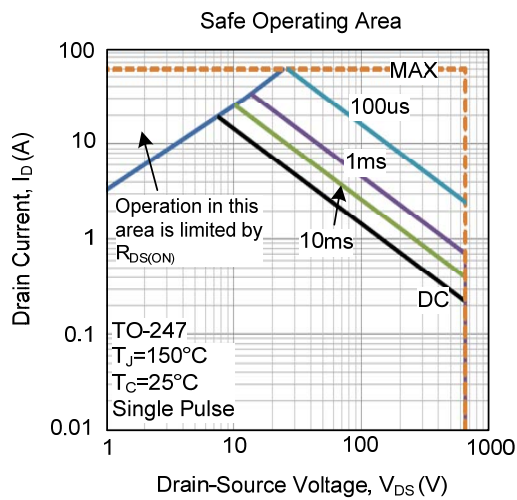


## ■ TYPICAL CHARACTERISTICS (Cont.)





### ■ TYPICAL CHARACTERISTICS (Cont.)



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